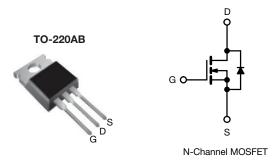


N-Channel 600V (D-S) Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	600				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.8				
Q _g max. (nC)	49				
Q _{gs} (nC)	13				
Q _{gd} (nC)	20				
Configuration	Single				

FEATURES

- Low gate charge Qg results in simple drive requirement
- Improved gate, avalanche and dynamic dV/dt ruggedness
- Fully characterized capacitance and avalanche voltage and current



APPLICATIONS

- Switch mode power supply (SMPS)
- Uninterruptible power supply
- High speed power switching

APPLICABLE OFF LINE SMPS TOPOLOGIES

- Active clamped forward
- · Main switch

ABSOLUTE MAXIMUM RATINGS (T C	= 25 °C, unl	less otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	600	Ň
Gate-Source Voltage			V _{GS}	± 30	- V
Continuous Drain Current	$V_{GS} \text{ at } 10 \text{ V} \qquad T_{C} = 25 \text{ T} $ $T_{C} = 100 \text{ T} $	T _C = 25 °C	- I _D	8.0	
		T _C = 100 °C		5.8	A
Pulsed Drain Current ^a			I _{DM}	37	
Linear Derating Factor				1.3	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	290	mJ	
Repetitive Avalanche Current ^a			I _{AR}	8.0	A
Repetitive Avalanche Energy ^a			E _{AR}	17	mJ
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$		PD	170	W	
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak temperature) ^d for 10 s		-	300		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in
Mounting Torque				1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Starting $T_J = 25$ °C, L = 6.8 mH, $R_g = 25 \Omega$, $I_{AS} = 9.2$ A (see fig. 12). c. $I_{SD} \le 9.2$ A, dl/dt ≤ 50 A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.

d. 1.6 mm from case.



IRF830P



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.75	

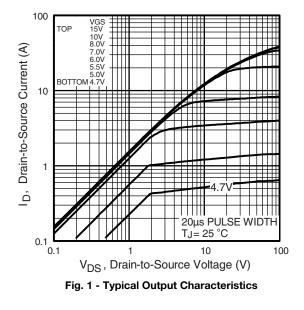
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		4			Į	Į	4
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$		600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referen	ce to 25 °C, I _D = 1 mA	-	660	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS}	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V	-	-	± 100	nA
Zoro Cato Voltago Drain Current	l	V _{DS} :	V _{DS} = 600 V, V _{GS} = 0 V		-	25	μA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 480 V	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 5.5 A ^b	-	0.8	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 5.5 A	5.5	-	-	S
Dynamic					-	-	
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$		-	1400	-	σF
Output Capacitance	C _{oss}	_	V _{DS} = 25 V,		180	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		7.1	-	
	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	1957	-	
Output Capacitance		$V_{GS} = 0 V$	V _{DS} = 480 V, f = 1.0 MHz	-	49	-	1
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 480 V	-	96	-	
Total Gate Charge	Qg			-	-	49	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 8.0\text{A}, \text{ V}_{DS} = 400 \text{ V}$		-	-	13	nC
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13 ^b	-	-	20	
Turn-On Delay Time	t _{d(on)}			-	13	-	-
Rise Time	t _r	V _{DD} :	V _{DD} = 300 V, I _D = 8.0 A		25	-	
Turn-Off Delay Time	t _{d(off)}	$B_{r} = 910$	$R_D = 35.5 \Omega$, see fig. 10 ^b	-	30	-	ns
Fall Time	t _f		ng = 66.6 11, 666 ng. 16	-	22	-]
Gate Input Resistance	R _g	f = 1 MHz, open drain		0.5	-	3.2	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol showing the		-	9.2	
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	37	A
Body Diode Voltage	V _{SD}	T _J = 25 °C	C, $I_S = 8.0 \text{ A}$, $V_{GS} = 0 \text{ V}^{\text{b}}$	-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 8.0 \text{ A}, dl/dt = 100 \text{ A/}\mu\text{s}^{\text{b}}$		-	530	800	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.0	4.4	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	-on is dor	ninated b	v Le and		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %. c. C_{oss} effective is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



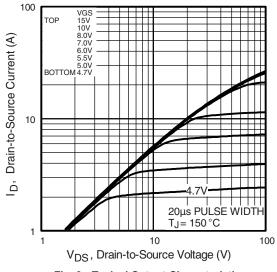


Fig. 2 - Typical Output Characteristics

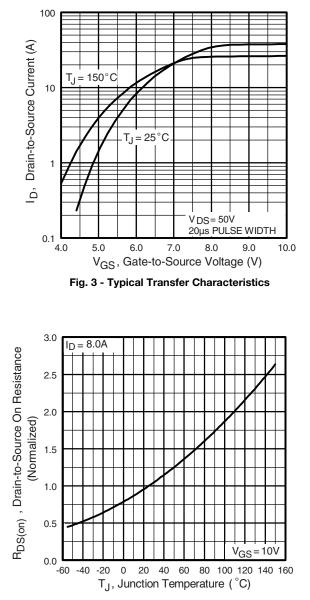


Fig. 4 - Normalized On-Resistance vs. Temperature

IRF830P

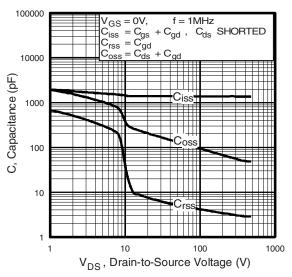


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

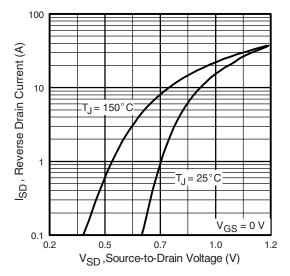


Fig. 7 - Typical Source-Drain Diode Forward Voltage

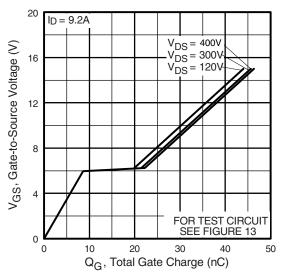


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

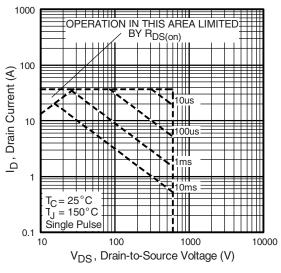


Fig. 8 - Maximum Safe Operating Area





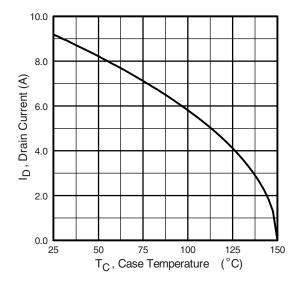


Fig. 9 - Maximum Drain Current vs. Case Temperature

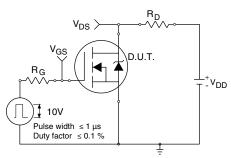


Fig. 10a - Switching Time Test Circuit

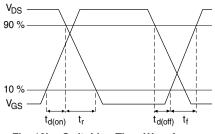


Fig. 10b - Switching Time Waveforms

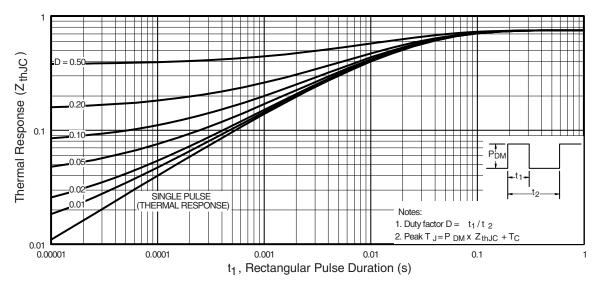


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

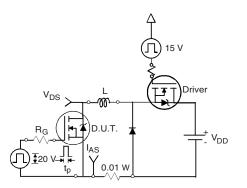


Fig. 12a - Unclamped Inductive Test Circuit

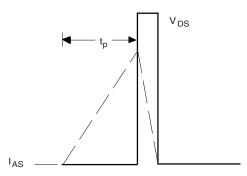


Fig. 12b - Unclamped Inductive Waveforms

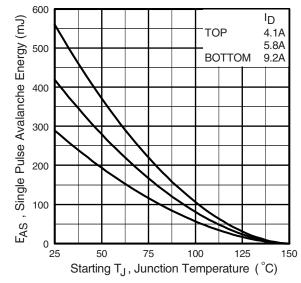
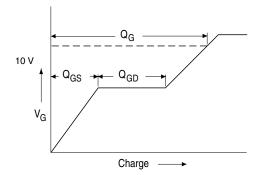


Fig. 12c - Maximum Avalanche Energy vs. Drain Current





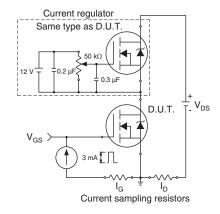
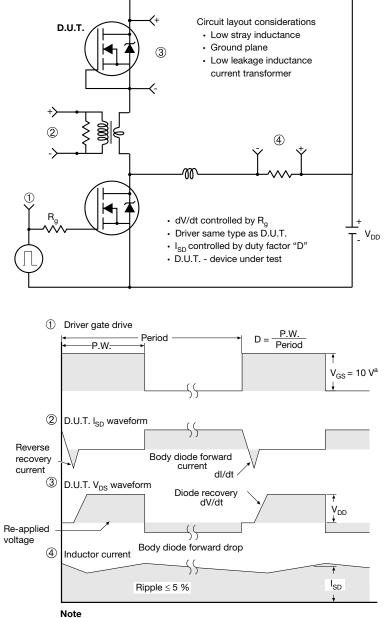


Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit

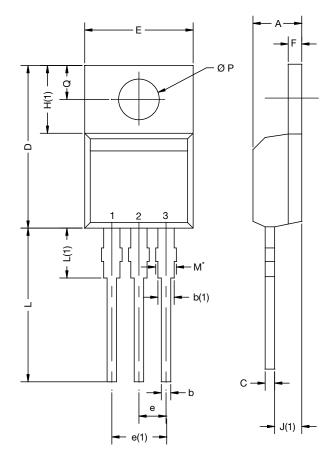


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220-1



DIM	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15- DWG: 603	0364-Rev. C, 1	14-Dec-15			

Note

- M^{\star} = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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